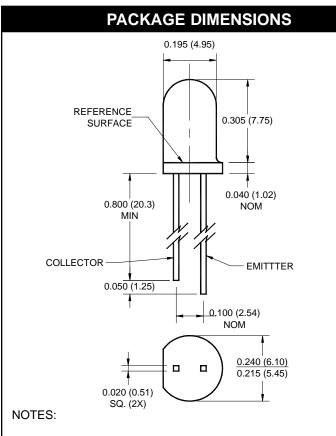


## PLASTIC SILICON INFRARED PHOTOTRANSISTOR

# QSD128



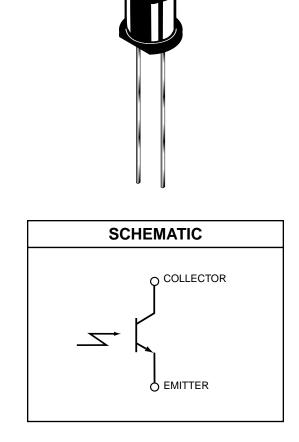
- 1. Dimensions for all drawings are in inches (mm).
- 2. Tolerance of  $\pm$  .010 (.25) on all non-nominal dimensions unless otherwise specified.

### DESCRIPTION

The QSD128 is a phototransistor encapsulated in an infrared transparent, black T-1 3/4 package.

#### FEATURES

- NPN Silicon Phototransistor
- Package Type: T-1 3/4
- Notched Emitter: QED12X/QED22X/QED23X
- Narrow Reception Angle: 24°C
- Daylight Filter
- Package Material and Color: Black Epoxy
- High Sensitivity





# QSD128

<b>ABSOLUTE MAXIMUM RATINGS</b> (T <sub>A</sub> = 25°C unless otherwise specified)						
Parameter	Symbol	Rating	Unit			
Operating Temperature	T <sub>OPR</sub>	-40 to +100	°C			
Storage Temperature	T <sub>STG</sub>	-40 to +100	°C			
Soldering Temperature (Iron) <sup>(2,3,4)</sup>	T <sub>SOL-I</sub>	240 for 5 sec	°C			
Soldering Temperature (Flow) <sup>(2,3)</sup>	T <sub>SOL-F</sub>	260 for 10 sec	°C			
Collector-Emitter Voltage	V <sub>CE</sub>	30	V			
Emitter-Collector Voltage	V <sub>EC</sub>	5	V			
Power Dissipation <sup>(1)</sup>	PD	100	mW			

#### NOTE:

1. Derate power dissipation linearly 1.33 mW/°C above 25°C.

2. RMA flux is recommended.

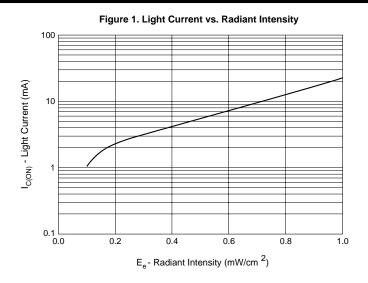
- 3. Methanol or isopropyl alcohols are recommended as cleaning agents.
- 4. Soldering iron 1/16" (1.6mm) minimum from housing.
- 5.  $\lambda$  = 880 nm, AlGaAs.

ELECTRICAL / OPTICAL CHARACTERISTICS (TA =25°C)								
PARAMETER	TEST CONDITIONS	SYMBOL	MIN	TYP	MAX	UNITS		
Peak Sensitivity Wavelength		λps	—	880	—	nm		
Reception Angle		θ	—	±12	—	Deg.		
Collector Emitter Dark Current	$V_{CE} = 10 \text{ V}, \text{ E}_{e} = 0$	I <sub>CEO</sub>		_	100	nA		
Collector Emitter Breakdown	$I_{C} = 1 \text{ mA}$	BVCEO	30	_		V		
Emitter Collector Breakdown	I <sub>E</sub> = 100 μA	BV <sub>ECO</sub>	5	—	—	V		
On-State Collector Current <sup>(5)</sup>	$E_e = 0.5 \text{ mW/cm}^2$ , $V_{CE} = 5 \text{ V}$	I <sub>C (ON)</sub>	1.60	—	_	mA		
Saturation Voltage <sup>(5)</sup>	$E_e = 0.5 \text{ mW/cm}^2$ , $I_C = 0.5 \text{ mA}$	VCE (SAT)	_	—	0.4	V		
Rise Time	$V_{CC} = 5 V, R_1 = 100 \Omega lc = 0.2 mA$	tr	—	7	—	μs		
Fall Time	$VCC = 5 V, R_{L} = 100 \Omega C = 0.2 MA$	t <sub>f</sub>	_	7	_			



### **PLASTIC SILICON INFRARED** PHOTOTRANSISTOR

# **QSD128**



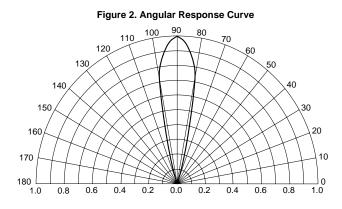
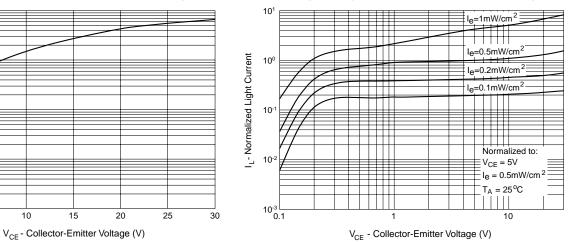
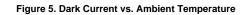
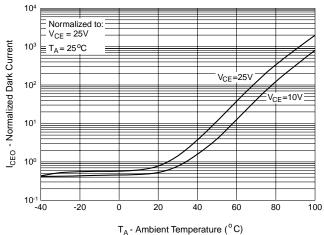


Figure 3. Dark Current vs. Collector - Emitter Voltage

Figure 4. Light Current vs. Collector - Emitter Voltage







10<sup>1</sup>

10<sup>0</sup>

10-

10-

10-3

0

5

10

15

I<sub>CEO</sub> - Dark Current (nA)



### PLASTIC SILICON INFRARED PHOTOTRANSISTOR

## QSD128

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